



AM/Pre Ammt A
1/11/03

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Abdurrahman Sezginer et al. PATENT APPLICATION
Serial No.: 10/074,561 Group Art Unit: 2881
Filed: February 12, 2002 Examiner:
For: OVERLAY ALIGNMENT METROLOGY
USING DIFFRACTION GRATINGS

Preliminary Amendment

Hon. Assistant Commissioner for Patents
Washington, D.C. 20231

Sir:

Prior to the first Office action, please add the
following new claims.

In the claims:

Please add claims 32 - 40 as follows:

32. (new) The method of claim 1, further comprising observing
at least one second test area on said substrate using a
camera, the second test area having a pattern built into
layers A and B for measuring any gross overlay errors, and
wherein determining the offset includes using gross overlay
measurements obtained from the camera.

33. (new) The method of claim 32, wherein said pattern in said
second test area comprises a box-in-box pattern.

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